Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/776,443	MILLER ET AL.	
Examiner	Art Unit	
Raj K. Jain	2664	

	SEARCHED					
SEARCHED						
Class	Subclass	Date	Examiner			
370	310,321 328,336	5/23/2005	RJ _.			
370	338,343					
370	347,397					
370	399					
370	395.21					
370	412-414					
370	409,465					
370	468,470					
370	442,498					
455	452.1					
455	452.2	4				

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

	DATE	EXMR
Master Node, dyanmic bandwidth, resizing, TDD, TDMA	5/23/2005	RJ
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